

**Search Notes**

Application/Control No.

10/659,307

Examiner

Cong-Lac Huynh

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2178

**SEARCHED**

Class	Subclass	Date	Examiner
715	500	11/16/2007	CLH
	501.1	11/16/2007	CLH
	512	11/16/2007	CLH
	500.1	11/16/2007	CLH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	512	11/16/2007	CLH
	500.1	11/19/2007	CLH
Interference Search History Printout		11/19/2007	CLH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (US PAT, USPGPUB, JPO, EPO, Derwent)	11/16/2007	CLH
ACM	11/16/2007	CLH
Google	11/16/2007	CLH